

# FDD8870 / FDU8870 N-Channel PowerTrench<sup>®</sup> MOSFET 30V, 160A, $3.9m\Omega$

### **General Description**

This N-Channel MOSFET has been designed specifically to improve the overall efficiency of DC/DC converters using either synchronous or conven tional swit ching PW M controllers. It has been optimized for low gate charge, low  $r_{\text{DS}(\text{ON})}$  and fast switching speed.

# ApplicationsDC/DC converters

# **Features** • r<sub>DS(ON)</sub> = 3.9mΩ V<sub>GS</sub> = 10V, I<sub>D</sub> = 35A

- r<sub>DS(ON)</sub> = 4.4mΩ, V<sub>GS</sub> = 4.5V, I<sub>D</sub> = 35A
- High performance trench technology for extremely low  $\ensuremath{^r\text{DS(ON)}}$
- · Low gate charge
- High power and current handling capability



D



I-PAK (TO-251AA)



**MOSFET Maximum Ratings** T<sub>C</sub> = 25°C unless otherwise noted

Symbol	Parameter	Ratings	Units	
V <sub>DSS</sub>	Drain to Source Voltage	30	V	
V <sub>GS</sub>	Gate to Source Voltage	±20	V	
ID	Drain Current			
	Continuous ( $T_C = 25^{\circ}C$ , $V_{GS} = 10V$ ) (Note 1)	160	Α	
	Continuous (T <sub>C</sub> = $25^{\circ}$ C, V <sub>GS</sub> = 4.5V) (Note 1)	150	А	
	Continuous ( $T_{amb}$ = 25°C, $V_{GS}$ = 10V, with $R_{\theta JA}$ = 52°C/W)	21	Α	
	Pulsed	Figure 4	Α	
E <sub>AS</sub>	Single Pulse Avalanche Energy (Note 2)	690	mJ	
P <sub>D</sub>	Power dissipation	160	W	
	Derate above 25°C	1.07	W/ºC	
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature	-55 to 175	°C	

GDS

# **Thermal Characteristics**

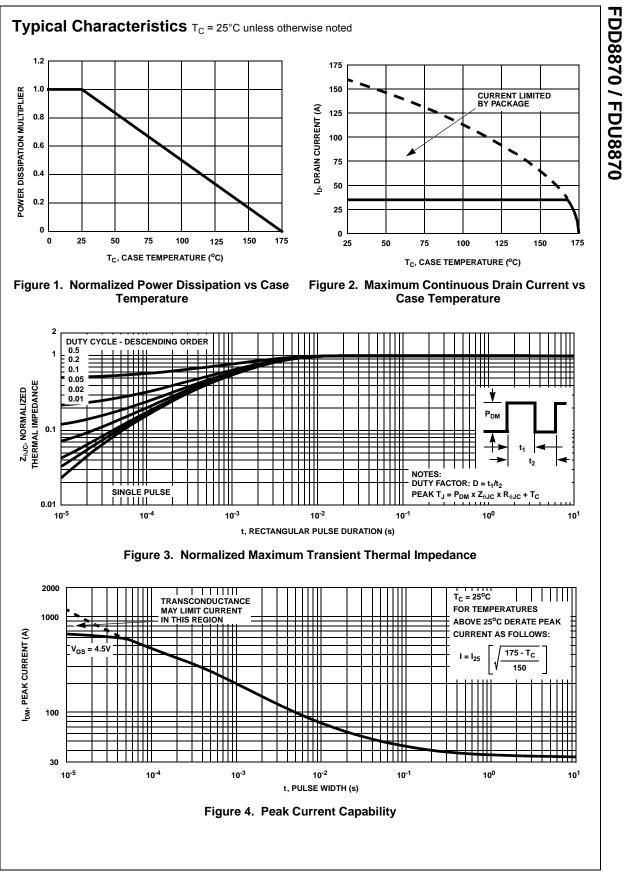
$R_{ extsf{ heta}JC}$	Thermal Resistance Junction to Case TO-252, TO-251	0.94	°C/W
$R_{\thetaJA}$	Thermal Resistance Junction to Ambient TO-252, TO-251	100	°C/W
$R_{\thetaJA}$	Thermal Resistance Junction to Ambient TO-252, 1in <sup>2</sup> copper pad area	52	°C/W

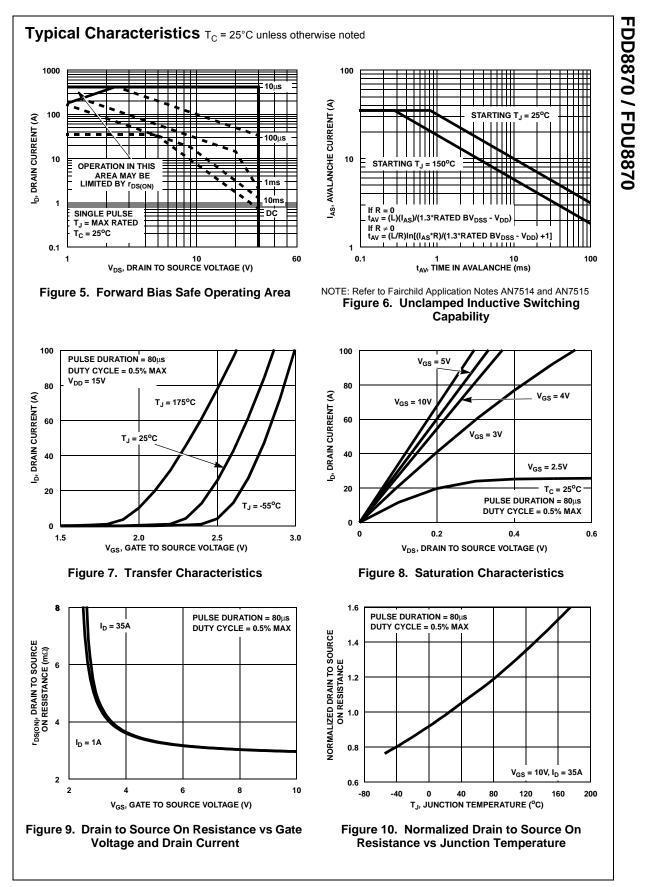
# March 2015

Device MarkingDeviceFDD8870FDD8870		Device Package Reel Size		Reel Size	Tape \	Nidth	Quar	ntity	
		TO-252AA 13"	13"	16mm N/A		2500 units 75 units			
FDU8	FDU8870 FDU8870		TO-251AA Tube						
	al Chara	acteristics T <sub>C</sub> = 25°C					1	ſ	
Symbol		Parameter	Test Co	onditions	Min	Тур	Мах	Unit	
Off Chara	cteristics	5							
B <sub>VDSS</sub>	Drain to So	ource Breakdown Voltage	I <sub>D</sub> = 250μA, V <sub>G</sub>	<sub>S</sub> = 0V	30	-	-	V	
			V <sub>DS</sub> = 24V			-	1		
DSS	Zero Gate	Voltage Drain Current	$V_{GS} = 0V$	T <sub>C</sub> = 150 <sup>o</sup> C	-	-	250	μA	
I <sub>GSS</sub>	Gate to Source Leakage Current		V <sub>GS</sub> = ±20V		-	-	±100	nA	
		-			ı				
	cteristics								
V <sub>GS(TH)</sub>	Gate to So	urce Threshold Voltage	$V_{GS} = V_{DS}, I_D =$		1.2	-	2.5	V	
	Drain to Source On Resistance		I <sub>D</sub> = 35A, V <sub>GS</sub> :		-	0.0032	0.0039		
r <sub>DS(ON)</sub>			I <sub>D</sub> = 35A, V <sub>GS</sub> :		-	0.0036	0.0044	Ω	
D3(0N)			I <sub>D</sub> = 35A, V <sub>GS</sub> : T <sub>J</sub> = 175 <sup>o</sup> C	= 10V,	-	0.0051	0.0063		
Dynamic	Characte	ristics							
C <sub>ISS</sub>	Input Capa	citance		a) (	-	5160	-	pF	
C <sub>OSS</sub>	Output Ca	pacitance	$V_{DS} = 15V, V_{G}$	<sub>S</sub> = 0V,	-	990	-	pF	
C <sub>RSS</sub>	Reverse Tr	ansfer Capacitance		f = 1MHz		590	-	pF	
R <sub>G</sub>	Gate Resis	te Resistance V <sub>GS</sub> = 0.5V, f = 1MHz		-	2.1	-	Ω		
Q <sub>g(TOT)</sub>	Total Gate	Charge at 10V	V <sub>GS</sub> = 0V to 10		-	91	118	nC	
Q <sub>g(5)</sub>	Total Gate	Charge at 5V	$V_{GS} = 0V$ to 5V	'	-	48	62	nC	
Q <sub>g(TH)</sub>	Threshold	Gate Charge	V <sub>GS</sub> = 0V to 1V	$V_{DD} = 15V$	-	5	6.5	nC	
Q <sub>gs</sub>	Gate to So	urce Gate Charge		I <sub>D</sub> = 35A I <sub>a</sub> = 1.0mA	-	14	-	nC	
Q <sub>gs2</sub>	Gate Char	ge Threshold to Plateau		'g I.OIIIA	-	9	-	nC	
Q <sub>gd</sub>	Gate to Dr	ain "Miller" Charge			-	18	-	nC	
	Charact	eristics (V <sub>GS</sub> = 10V)							
ON	Turn-On Ti	me			-	-	139	ns	
td(ON)	Turn-On D	elay Time			-	9	-	ns	
<u> </u>	Rise Time		V <sub>DD</sub> = 15V, I <sub>D</sub> =	= 35A	-	83	-	ns	
d(OFF)	Turn-Off D	elay Time	$V_{GS} = 10V, R_{GS} = 3.3\Omega$		-	83	-	ns	
t <sub>f</sub>	Fall Time					42	-	ns	
OFF	Turn-Off Ti	me			-	-	189	ns	
	Irce Diod	e Characteristics	1				. <u> </u>		
V <sub>SD</sub>	Source to Drain Diode Voltage		I <sub>SD</sub> = 35A		-	-	1.25	V	
· 3D			I <sub>SD</sub> = 15A		-	-	1.0	V	
t <sub>rr</sub>	Reverse R	ecovery Time	$I_{SD}$ = 35A, d $I_{SD}$	₀/dt = 100A/μs	-	-	37	ns	
	Reverse Recovered Charge		I <sub>SD</sub> = 35A, dI <sub>SD</sub>						

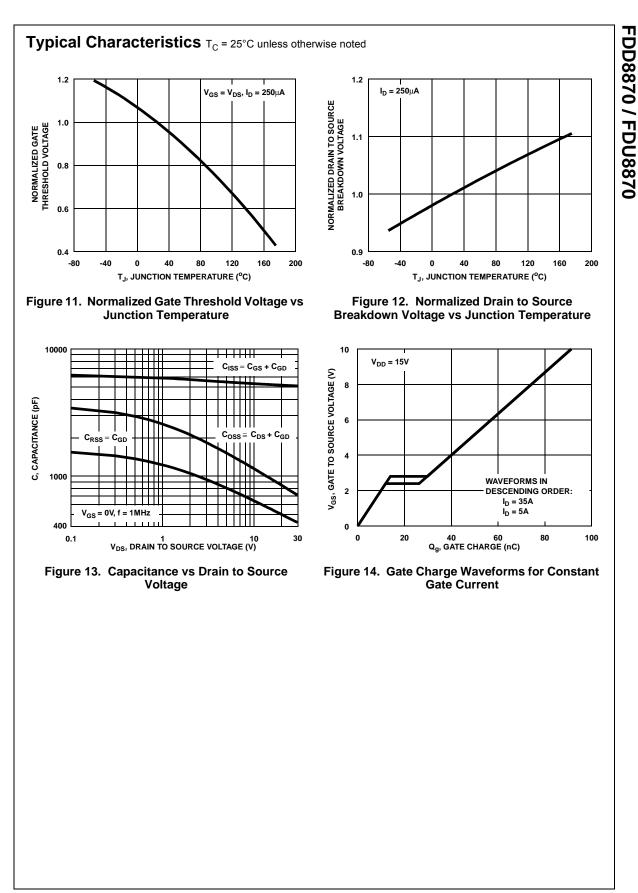
Notes: 1: Package current limitation is 35A. 2: Starting  $T_J$  = 25°C, L = 1.77mH, I<sub>AS</sub> = 28A, V<sub>DD</sub> = 27V, V<sub>GS</sub> = 10V.

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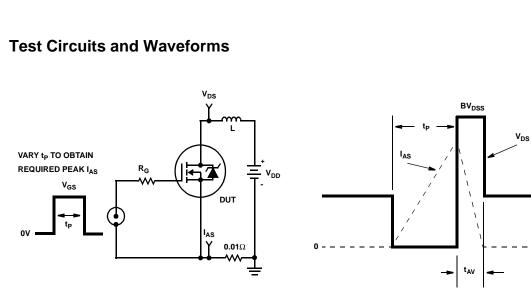




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 $V_{DD}$ 

Figure 16. Unclamped Energy Waveforms

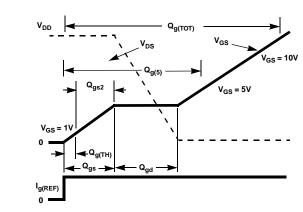


Figure 18. Gate Charge Waveforms

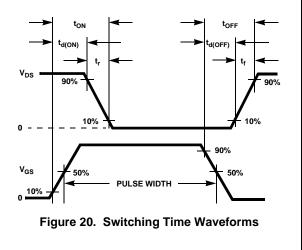


Figure 15. Unclamped Energy Test Circuit

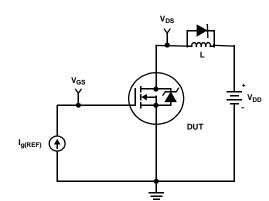


Figure 17. Gate Charge Test Circuit

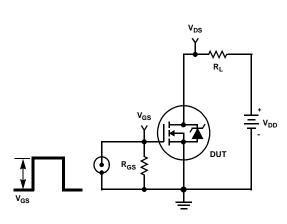


Figure 19. Switching Time Test Circuit

## Thermal Resistance vs. Mounting Pad Area

The max imum rated junct ion temperature, T  $_{JM}$ , and t he thermal resistance of the heat dissipating path determines the maximum allowable device power dissipation, P<sub>DM</sub>, in an application. Therefore t he application's ambient temperature, T<sub>A</sub> (<sup>o</sup>C), and thermal resistance R<sub>0JA</sub> (<sup>o</sup>C/W) must be rev iewed to ensure that T<sub>JM</sub> is never ex ceeded. Equation 1 mathematically represents the relationship and serves as the basis for establishing the rating of the part.

$$P_{DM} = \frac{(T_{JM} - T_A)}{R_{\theta JA}}$$
(EQ. 1)

In us ing surf ace m ount dev ices s uch as t he T O-252 package, the environment in which it is applied will have a significant inf luence on t he part's cur rent and m aximum power dissipation ratings. Precise determination of  $P_{DM}$  is complex and influenced by many factors:

- 1. Mounting pad area onto which the device is attached and whether there is copper on one side or both sides of the board.
- 2. The number of copper layers and the thickness of the board.
- 3. The use of external heat sinks.
- 4. The use of thermal vias.
- 5. Air flow and board orientation.
- For non steady state applications, the pulse width, the duty cycle and the transient thermal response of the part, the board and the environment they are in.

Fairchild provides t hermal i nformation t o as sist the designer's preliminary application evaluat ion. F igure 21 defines the R  $_{\theta,JA}$  f or the device as a function of the top copper (component s ide) area. T his is f or a horizont ally positioned FR-4 board with 1oz copper after 1000 seconds of steady state power with no air flow. This graph provides the necessary information for calculation of the steady state junction temperature or power dissipat ion. P ulse applications can be ev aluated us ing t he F airchild device Spice thermal model or m anually utilizing the norm alized maximum transient thermal impedance curve.

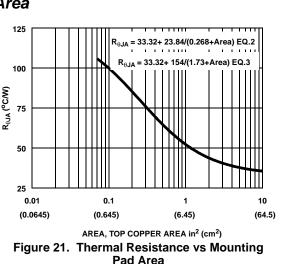
Thermal resistances corresponding to other copper areas can be obt ained from Figure 21 or by calc ulation using Equation 2 or 3. Equation 2 is used for copper area defined in inches square and equation 3 is for area in centimeters square. The area, in square inches or square centimeters is the top copper area including the gate and source pads.

$$R_{\theta JA} = 33.32 + \frac{23.84}{(0.268 + Area)}$$
 (EQ. 2)

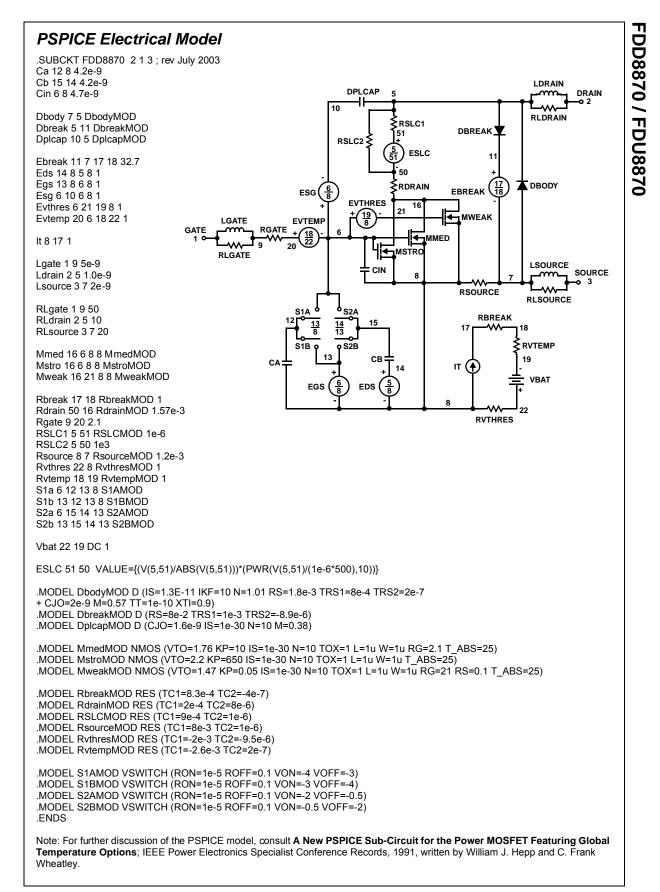
Area in Inches Squared

$$R_{\theta JA} = 33.32 + \frac{154}{(1.73 + Area)}$$
(EQ. 3)

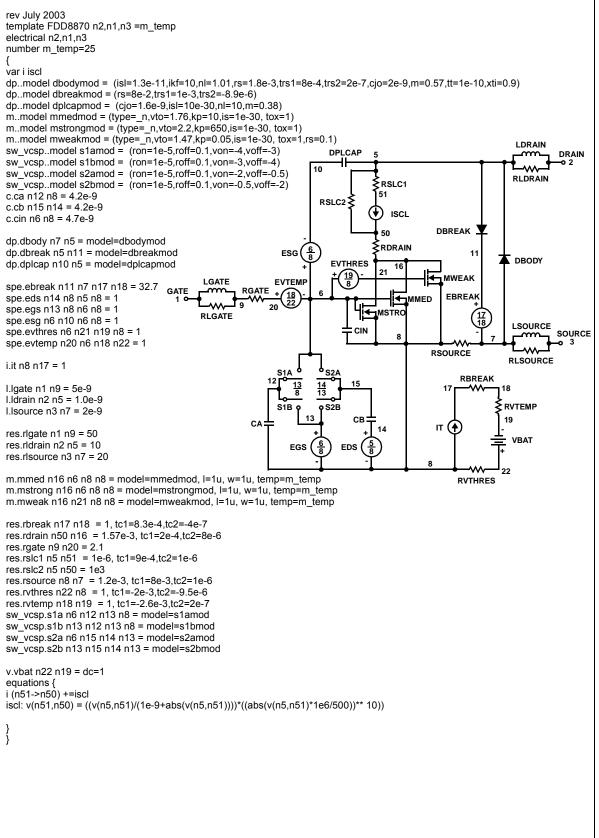
Area in Centimeters Squared



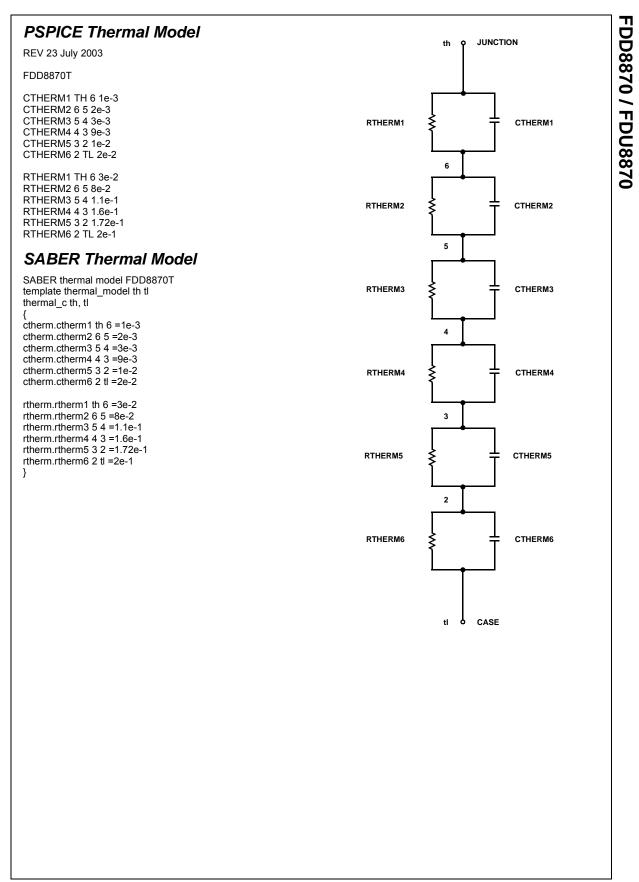
# FDD8870 / FDU8870



# SABER Electrical Model

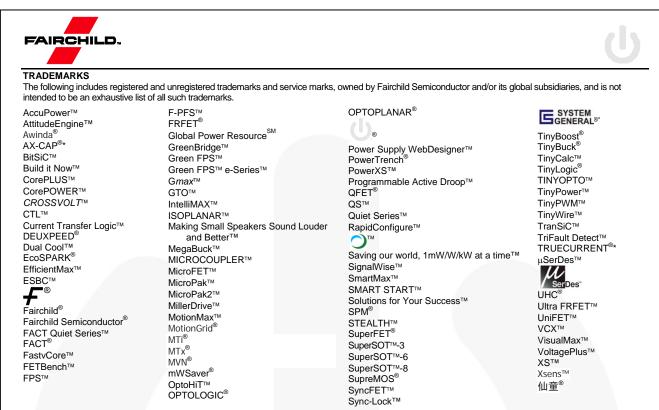


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